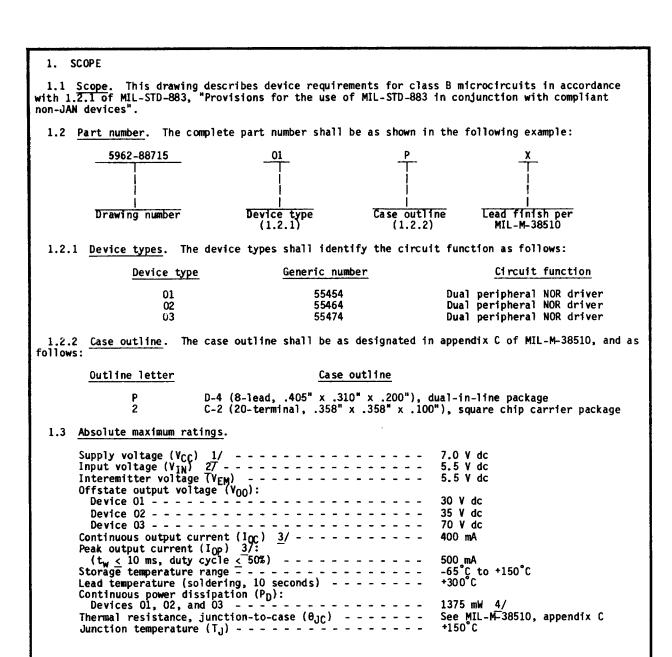
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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.



Voltage values are with respect to ground.

7/ This is the voltage between two emitters of a multiple-emitter transistor.

3/ Both halves of these dual circuits may conduct rated current simultaneously; however, power dissipation averaged over a short time interval must fall within the continuous power dissipation ratings.

 $\frac{1}{2}$ Devices 01, 02, and 03 derate above $T_A = +25^{\circ}C$ at 11.0 mW/ $^{\circ}C$.

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1.4 Recommended operating conditions.

Supply voltage range (V_{CC}) - - - - - - - - - - - - - +4.5 V dc to +5.5 V dc Ambient operating temperature range (T_A) - - - - - - - - - - - - - - - 55 °C to +125 °C Minimum high level input voltage (T_{IH}) - - - - - - - - - - - - - 0.8 V dc 0.8 V dc

2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
 - 3.2.3 Case outline. The case outline shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range.

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	TABLE 1	. Electr	·ical p	erformanc	e chara	cteristi	cs.	.		
Test	Symbol	-55	Condi	itions A <u><</u> +125°C		Device type	 Group A subgroups			 Uni [.]
		unless	otherw	ise specif	ied			Min	Max	<u> </u>
Input clamp voltage	AIC	V _{CC} = 4.	5 V, I	i = -12 mA	\ j	A11	1,2,3	<u>i</u>	-1.5	į v
High level output current	IOH	 V _{CC} = 4.	5 V 8 V	V _{OH} = 30	v	01	 1,2,3 	! ! !	 30 0 	 μ Α
				V _{OH} = 35	v	02	 	; 	! 	
] [V _{OH} = 70	v	03		 	! 	,
Low level output voltage	V _{OL1}	VCC = 4.1 VIH = 2.0	$I_{OL} = 4.5 \text{ Y}$ $I_{OL} = 100 \text{ mA}$ $I_{OL} = 300 \text{ mA}$		mA	All	1,2,3		0.5	V
	V _{OL2}	! !			mA) 			0.8) !
High level input current	I _{IH1}	V _{CC} = 5.	5 V	V _{IN} = 5.5	5 V	All	 1,2,3 		1.0	 mA
	I _{IH2}	[]]		 V _{IN} = 2.4	V			! ! !	40	μ Α
Low level input current	IIL	V _{CC} = 5.	5 V, V	IN = 0.4 V	,	A11	1,2,3] 	-1.6	l ImA I
High level supply current (outputs	Іссн	V _{CC} = 5.	5 V, V	IN = 0 V	 -	01	1,2,3		17	mA
high)	<u> </u>	<u> </u>				02,03	<u> </u>	<u> </u>	19	<u> </u>
Low level supply current (output low)	ICCL	VCC = 5.	$5.5 \text{ V, V}_{IN} = 5.0 \text{ V}$		/ <u>i</u>	01	1,2,3	<u>i</u>	79	l mA
Current (output low)		<u> </u>			i	02,03	<u>i </u>	<u> </u>	85	
Functional tests		See 4.3.	1c and	figure 2	i		7,8	i !	<u> </u>	<u> </u>
Propagation delay time,	t _{PLH}	 V _{CC} = 5.0	ο ν, ι	200 m/	\ <u> </u>	01	9	ļ	35	ns
low to high level output		CL = 15 See figu	pr, R _L re 3	= 5 0Ω	<u> </u>	02,03		<u> </u>	65	!
		1			ļ	01	10,11	 	55	
					- 1	02,03	<u> </u>	1	65	¦

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Test	Symbol	Conditions -55°C < T _A < +125°C,	Device	Group A	Limits		Unit:
		-55°C < T _A < +125°C, unless otherwise specified	type	subgroups	Min	Max	j
Propagation delay time	 t _{PHL}	$V_{CC} = 5.0 \text{ V}, I_0 = 200 \text{ mA}$	01	9,10,11		35	ns
high to low level output	<u> </u>	$ V_{CC} = 5.0$ V, $I_0 = 200$ mA $ C_L = 15$ pF, $R_L = 50\Omega$ See figure 3	02,03			50	
	l t _{TLH}	 	01	 9		8.0	ns
to high level output	 	 	02,03	10,11		25	
			01			10	
			02,03		 	25	
	tTHL		01	9		12	ns
to low level output	 	1	02,03	<u> </u>		20	
		1	01	10,11		14	ļ
	1	1	02,03]		l 20	i I

- 3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.
- 3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in MIL-BUL-103 (see 6.6 herein).
- 3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.9 <u>Verification and review</u>. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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Device types	01, 02,	, and 03
Case outline	Р	2
Terminal number	 Terminal 	symbol
1	1A	NC
2	1B	1A
3	1 1Y	NC
2 3 4	GND	NC
5	2Y	1B
6 7	2A	NC
7	2B	1Y
8	V _{CC}	NC
9		NC
10		GND
11		NC
12		2Y
13		NC
14	1	NC
15	[2A
16	!	NC
17	!	2B
18		NC
19	<u> </u>	NC
20	! -	VCC

FIGURE 1. Terminal connections.

Inp	uts	 Output Y
A	В	
L L H	 L H L H	H (off state) L (on state) L (on state) L (on state)

Positive logic: $Y = \overline{A + B}$ or \overline{AB} FIGURE 2. Truth table (each driver).

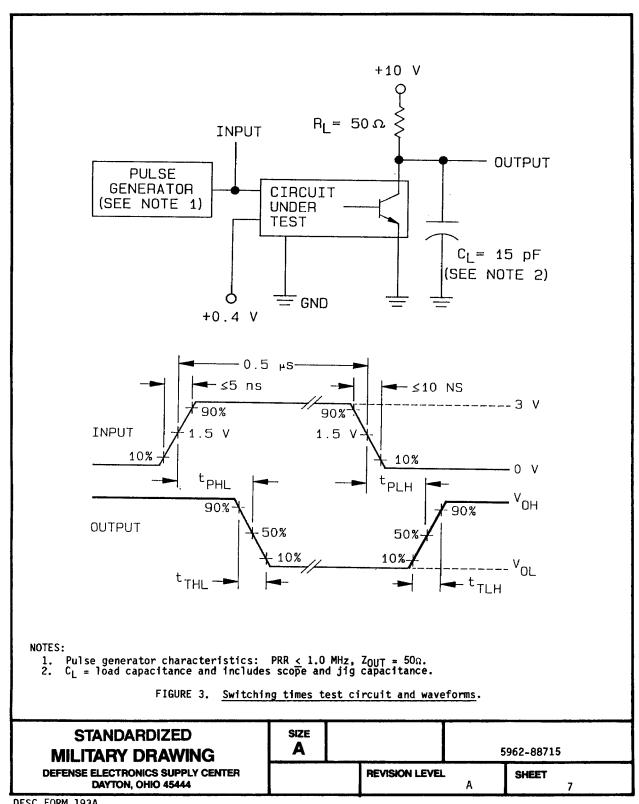
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- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883:
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-SID-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroups 7 and 8 shall include verification of the truth table.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	
 Final electrical test parameters (method 5004)	1*,2,3,7,9
Group A test requirements (method 5005)	1,2,3,7,8 9,10,11
 Groups C and D end-point electrical parameters (method 5005)	1,2,3

^{*} PDA applies to subgroup 1.

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- 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test conditions, method 1005 of MIL-STD-883:
 - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
 - 6. NOTES
- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
 - 6.2 Replaceability. Replaceability is determined as follows:
 - a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
 - b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/12910.
- 6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD form 1693, Engineering Change Proposal (Short Form).
- 6.4 Record of users. Military and industrial users shall inform Defense Electronic Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6022.
- 6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.6 Approved source of supply. An approved source of supply is listed in MIL-BUL-103.

Additional sources will be added to MIL-BUL-103 as they become available. The vendor listed in MIL-BUL-103 has agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS. The approved source of supply listed below is for information purposes only and is current to the date of the last action of this document.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1</u> /	Replacement military specification part number
5962-88715012X	34333	SG55454BL/883B	
5962 -8871502PX	34333	SG55464BY/883B	M38510/12910BPX
5962-88715022X	34333	SG55464BL/883B	
5962-8871503PX	34333	SG55474BY/883B	
5962-88715032X	34333	SG55474BL/883B	

1/ Caution. Do not use this number for item acquisition. Items acquired by this number may not satisfy the performance requirements of this drawing.

> Vendor CAGE number

> > 34333

Vendor name and address

Silicon General, Inc. 11861 Western Avenue Garden Grove, CA 92641

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